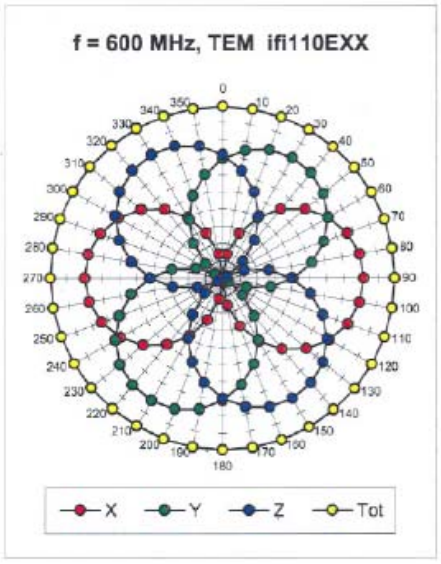
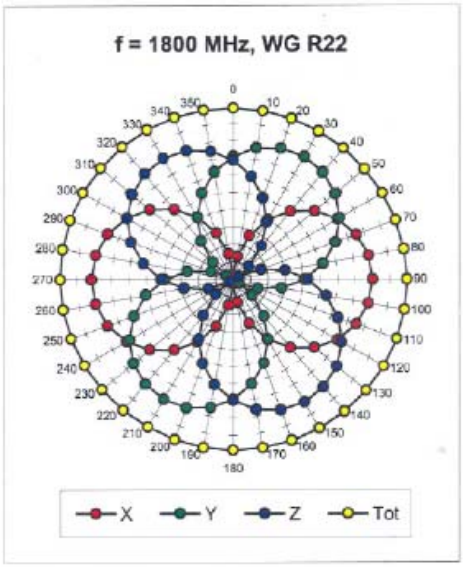
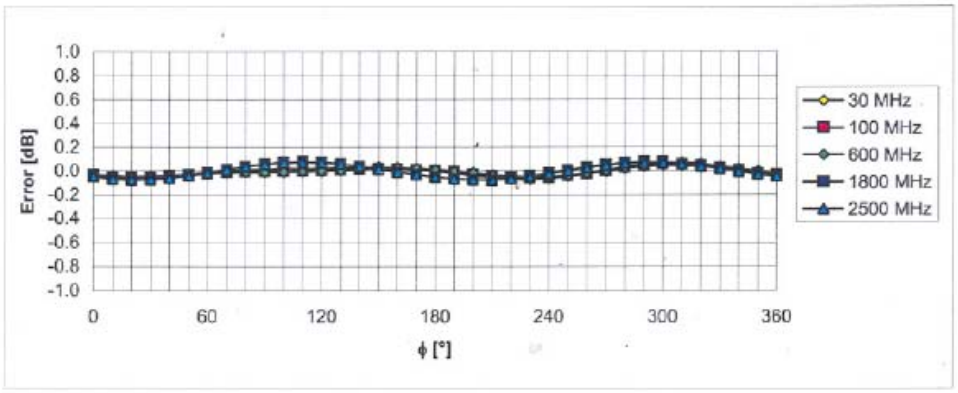
ET3DV6 SN:1788 September 26, 2007

Receiving Pattern (ϕ), ϑ = 0°





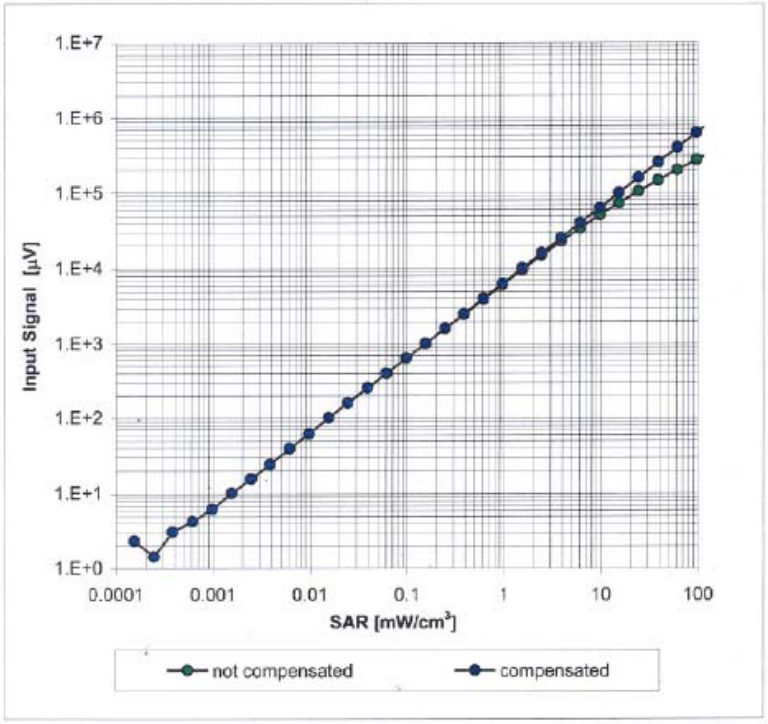


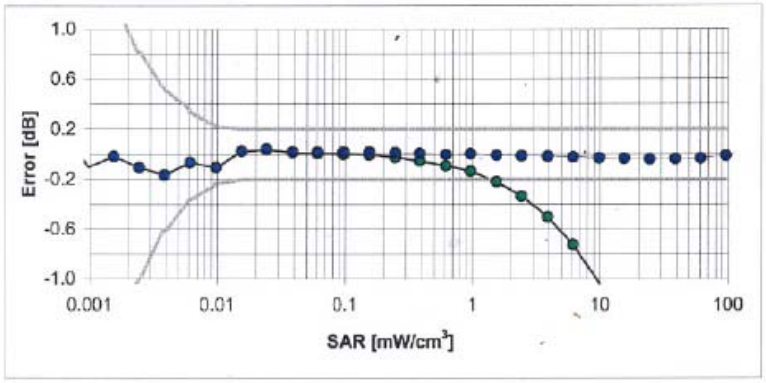
Uncertainty of Axial Isotropy Assessment: ± 0.5% (k=2)

ET3DV6 SN:1788 September 26, 2007

Dynamic Range f(SAR_{head})

(Waveguide R22, f = 1800 MHz)

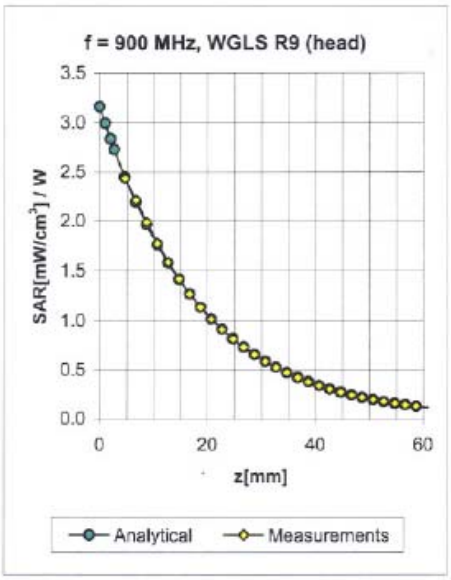


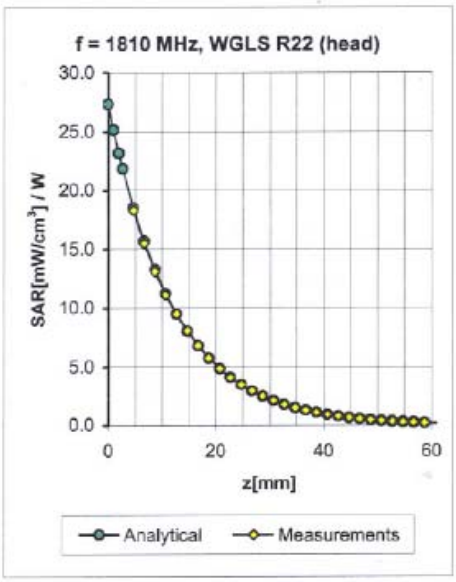


Uncertainty of Linearity Assessment: ± 0.6% (k=2)

ET3DV6 SN:1788 September 26, 2007

Conversion Factor Assessment





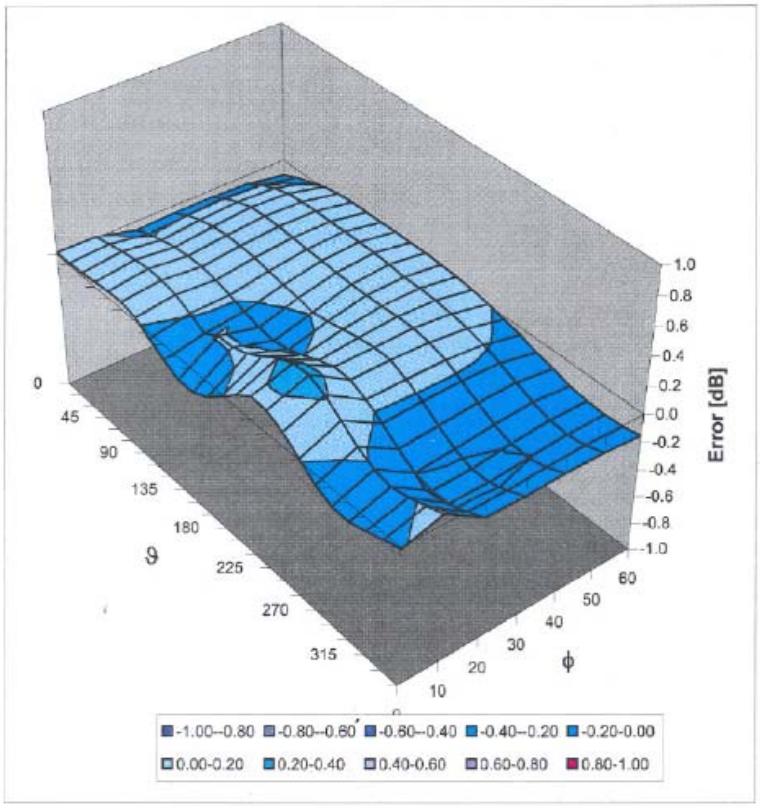
f [MHz]	Validity [MHz][c]	TSL	Permittivity	Conductivity	Alpha	Depth	ConvF Uncertainty
900	± 50 / ± 100	Head	41.5 ± 5%	0.97 ± 5%	0.22	3.28	6.54 ± 11.0% (k=2)
1810	± 50 / ± 100	Head	40.0 ± 5%	1.40 ± 5%	0.59	2.15	5.28 ± 11.0% (k=2)
2000	± 50 / ± 100	Head	40.0 ± 5%	1.40 ± 5%	0.60	2.23	4.87 ± 11.0% (k=2)
2450	± 50 / ± 100	Head	39.2 ± 5%	1.80 ± 5%	0.61	2.39	4.58 ± 11.8% (k=2)
900	± 50 / ± 100	Body	55.0 ± 5%	1.05 ± 5%	0.28	2.94	6.37 ± 11.0% (k=2)
1810	± 50 / ± 100	Body	53.3 ± 5%	1.52 ± 5%	0.63	2.39	4.75 ± 11.0% (k=2)
2000	± 50 / ± 100	Body	53.3 ± 5%	1.52 ± 5%	0.63	2.33	4.36 ± 11.0% (k=2)
2450	± 50 / ± 100	Body	52.7 ± 5%	1.95 ± 5%	0.61	2.58	4.17 ± 11.8% (k=2)

[c] The validity of ± 100 MHz only applies for DASY v4.4 and higher (see Page 2). The uncertainty is the RSS of the ConvF uncertainty at calibration frequency and the uncertainty for the indicated frequency band.

ET3DV6 SN:1788 September 26, 2007

Deviation from Isotropy in HSL

Error (ϕ, ϑ), f = 900 MHz



Uncertainty of Spherical Isotropy Assessment: ± 2.6% (k=2)

Calibration Laboratory of
Schmid & Partner
Engineering AG
Zeughausstrasse 43, 8004 Zurich, Switzerland

S Schweizerischer Kalibrierdienst
C Service suisse d'étalonnage
S Servizio svizzero di taratura
S Swiss Calibration Service

Accredited by the Swiss Accreditation Service (SAS)
The Swiss Accreditation Service is one of the signatories to the EA Multilateral Agreement for the recognition of calibration certificates

Accreditation No.: **SCS 108**

Client **Sporton (Auden)** Certificate No: **EX3-3514_Jan08**

CALIBRATION CERTIFICATE

Object	EX3DV3 - SN:3514
Calibration procedure(s)	QA CAL-01.v6 and QA CAL.14.v3 Calibration procedure for dosimetric E-field probes
Calibration date:	January 31, 2008
Condition of the calibrated item	In Tolerance

This calibration certificate documents the traceability to national standards, which realize the physical units of measurements (SI).
The measurements and the uncertainties with confidence probability are given on the following pages and are part of the certificate.

All calibrations have been conducted in the closed laboratory facility: environment temperature (22 ± 3)°C and humidity < 70%.

Calibration Equipment used (M&TE critical for calibration)

Primary Standards	ID #	Cal Date (Calibrated by, Certificate No.)	Scheduled Calibration
Power meter E4419B	GB41293874	29-Mar-07 (METAS, No. 217-00670)	Mar-08
Power sensor E4412A	MY41495277	29-Mar-07 (METAS, No. 217-00670)	Mar-08
Power sensor E4412A	MY41498087	29-Mar-07 (METAS, No. 217-00670)	Mar-08
Reference 3 dB Attenuator	SN: S5054 (3c)	8-Aug-07 (METAS, No. 217-00719)	Aug-08
Reference 20 dB Attenuator	SN: S5086 (20b)	29-Mar-07 (METAS, No. 217-00671)	Mar-08
Reference 30 dB Attenuator	SN: S5129 (30b)	8-Aug-07 (METAS, No. 217-00720)	Aug-08
Reference Probe ES3DV2	SN: 3013	2-Jan-08 (SPEAG, No. ES3-3013_Jan08)	Jan-09
DAE4	SN: 654	20-Apr-07 (SPEAG, No. DAE4-654_Apr07)	Apr-08

Secondary Standards	ID #	Check Date (in house)	Scheduled Check
RF generator HP 8648C	US3642U01700	4-Aug-99 (SPEAG, in house check Oct-07)	In house check: Oct-09
Network Analyzer HP 8753E	US37390585	18-Oct-01 (SPEAG, in house check Oct-07)	In house check: Oct-08

	Name	Function	Signature
Calibrated by:	Katja Pokovic	Technical Manager	
Approved by:	Niels Kuster	Quality Manager	

Issued: January 31, 2008

Calibration Laboratory of
Schmid & Partner
Engineering AG
Zeughausstrasse 43, 8004 Zurich, Switzerland

S Schweizerischer Kalibrierdienst
C Service suisse d'étalonnage
S Servizio svizzero di taratura
S Swiss Calibration Service

Accredited by the Swiss Accreditation Service (SAS)
The Swiss Accreditation Service is one of the signatories to the EA Multilateral Agreement for the recognition of calibration certificates

Accreditation No.: **SCS 108**

Glossary:

TSL	tissue simulating liquid
NORMx,y,z	sensitivity in free space
ConF	sensitivity in TSL / NORMx,y,z
DCP	diode compression point
Polarization φ	φ rotation around probe axis
Polarization ϑ	ϑ rotation around an axis that is in the plane normal to probe axis (at measurement center), i.e., ϑ = 0 is normal to probe axis

Calibration is Performed According to the Following Standards:

a) IEEE Std 1528-2003, "IEEE Recommended Practice for Determining the Peak Spatial-Averaged Specific Absorption Rate (SAR) in the Human Head from Wireless Communications Devices: Measurement Techniques", December 2003
b) IEC 62209-1, "Procedure to measure the Specific Absorption Rate (SAR) for hand-held devices used in close proximity to the ear (frequency range of 300 MHz to 3 GHz)", February 2005

Methods Applied and Interpretation of Parameters:

- *NORMx,y,z:* Assessed for E-field polarization ϑ = 0 (f ≤ 900 MHz in TEM-cell; f > 1800 MHz: R22 waveguide). NORMx,y,z are only intermediate values, i.e., the uncertainties of NORMx,y,z does not effect the E^2-field uncertainty inside TSL (see below *ConvF*).
- *NORM(f)x,y,z = NORMx,y,z * frequency_response* (see Frequency Response Chart). This linearization is implemented in DASY4 software versions later than 4.2. The uncertainty of the frequency response is included in the stated uncertainty of *ConvF*.
- *DCPx,y,z:* DCP are numerical linearization parameters assessed based on the data of power sweep (no uncertainty required). DCP does not depend on frequency nor media.
- *ConvF and Boundary Effect Parameters:* Assessed in flat phantom using E-field (or Temperature Transfer Standard for f ≤ 800 MHz) and inside waveguide using analytical field distributions based on power measurements for f > 800 MHz. The same setups are used for assessment of the parameters applied for boundary compensation (alpha, depth) of which typical uncertainty values are given. These parameters are used in DASY4 software to improve probe accuracy close to the boundary. The sensitivity in TSL corresponds to *NORMx,y,z * ConvF* whereby the uncertainty corresponds to that given for *ConvF*. A frequency dependent *ConvF* is used in DASY version 4.4 and higher which allows extending the validity from ± 50 MHz to ± 100 MHz.
- *Spherical isotropy (3D deviation from isotropy)*: in a field of low gradients realized using a flat phantom exposed by a patch antenna.
- *Sensor Offset*: The sensor offset corresponds to the offset of virtual measurement center from the probe tip (on probe axis). No tolerance required.

Probe EX3DV3

SN:3514

Manufactured:	December 15, 2002
Last calibrated:	February 21, 2007
Recalibrated:	January 31, 2008

Calibrated for DASY Systems

(Note: non-compatible with DASY2 system!)

EX3DV3 SN:3514 January 31, 2008

DASY - Parameters of Probe: EX3DV3 SN:3514

Sensitivity in Free Space[A] Diode Compression[B]

NormX	**0.650** ± 10.1%	$\mu V/(V/m)^2$	DCP X	**95** mV
NormY	**0.690** ± 10.1%	$\mu V/(V/m)^2$	DCP Y	**93** mV
NormZ	**0.580** ± 10.1%	$\mu V/(V/m)^2$	DCP Z	**96** mV

Sensitivity in Tissue Simulating Liquid (Conversion Factors)

Please see Page 8.

Boundary Effect

TSL **2300 MHz** **Typical SAR gradient: 10 % per mm**

Sensor Center to Phantom Surface Distance		**2.0 mm**	**3.0 mm**
SAR_{be} [%]	Without Correction Algorithm	5.9	3.3
SAR_{be} [%]	With Correction Algorithm	0.5	0.8

TSL **2600 MHz** **Typical SAR gradient: 11 % per mm**

Sensor Center to Phantom Surface Distance		**2.0 mm**	**3.0 mm**
SAR_{be} [%]	Without Correction Algorithm	6.3	3.4
SAR_{be} [%]	With Correction Algorithm	0.1	0.3

Sensor Offset

Probe Tip to Sensor Center	**1.0** mm

The reported uncertainty of measurement is stated as the standard uncertainty of measurement multiplied by the coverage factor k=2, which for a normal distribution corresponds to a coverage probability of approximately 95%.

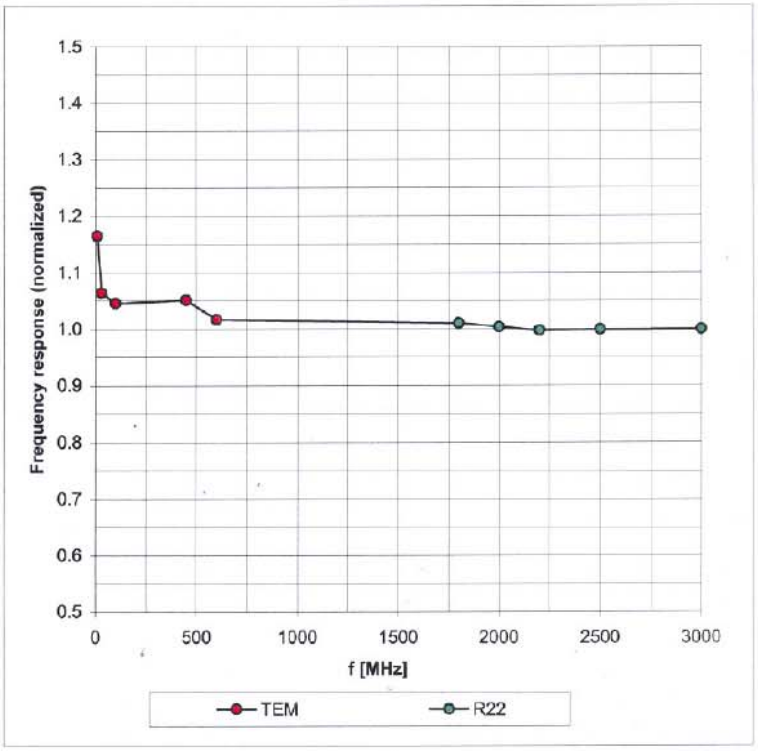
[A] The uncertainties of NormX,Y,Z do not affect the E^2-field uncertainty inside TSL (see Page 8).

[B] Numerical linearization parameter: uncertainty not required.

EX3DV3 SN:3514 January 31, 2008

Frequency Response of E-Field

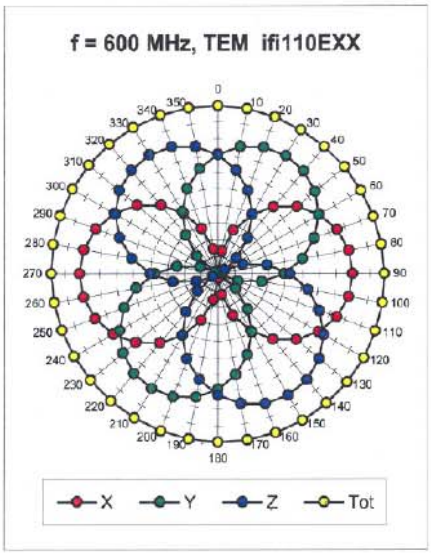
(TEM-Cell:ifi110 EXX, Waveguide: R22)

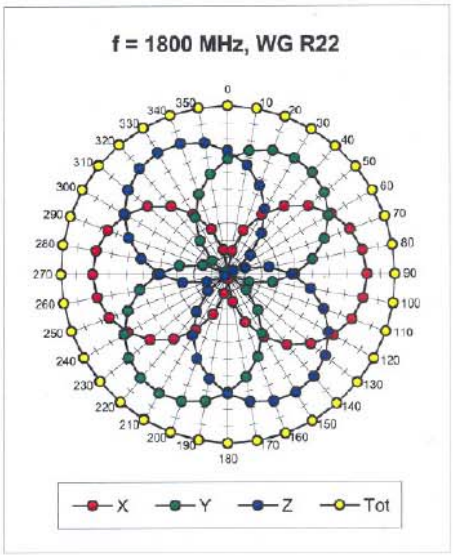


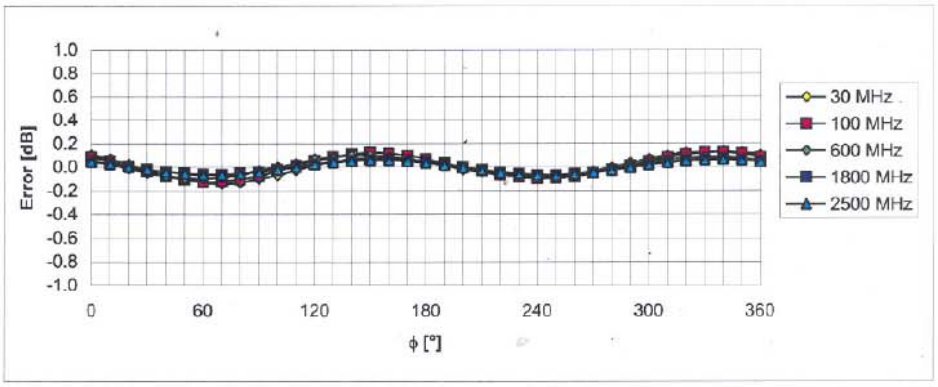
Uncertainty of Frequency Response of E-field: ± 6.3% (k=2)

EX3DV3 SN:3514 January 31, 2008

Receiving Pattern (ϕ), ϑ = 0°





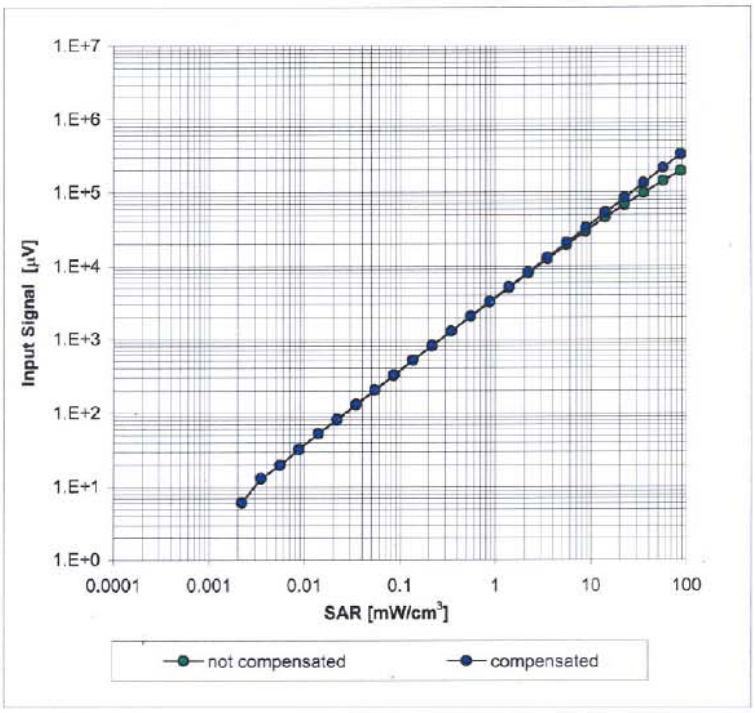


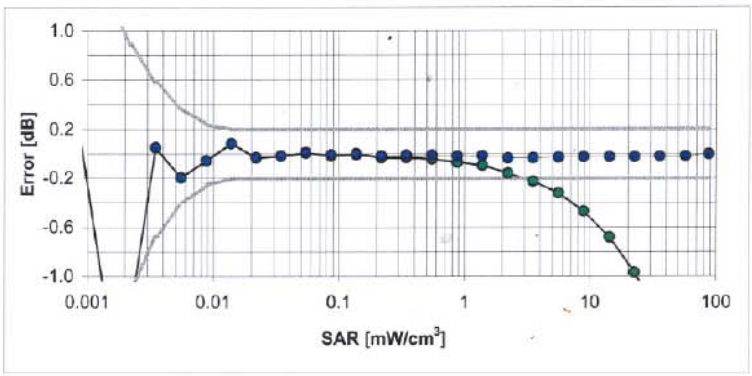
Uncertainty of Axial Isotropy Assessment: ± 0.5% (k=2)

EX3DV3 SN:3514 January 31, 2008

Dynamic Range f(SAR_{head})

(Waveguide R22, f = 1800 MHz)

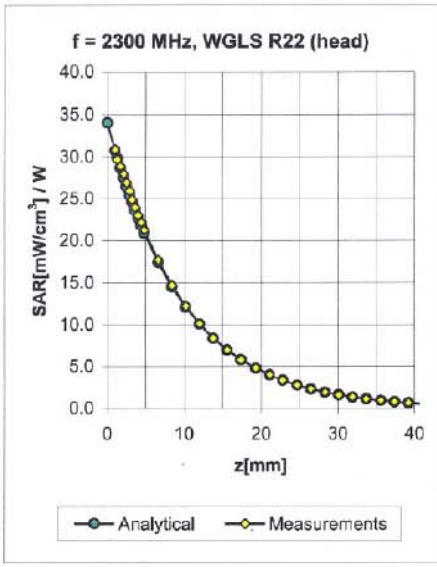


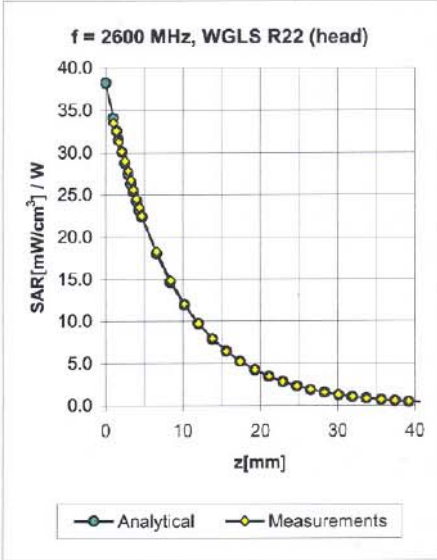


Uncertainty of Linearity Assessment: ± 0.6% (k=2)

EX3DV3 SN:3514 January 31, 2008

Conversion Factor Assessment





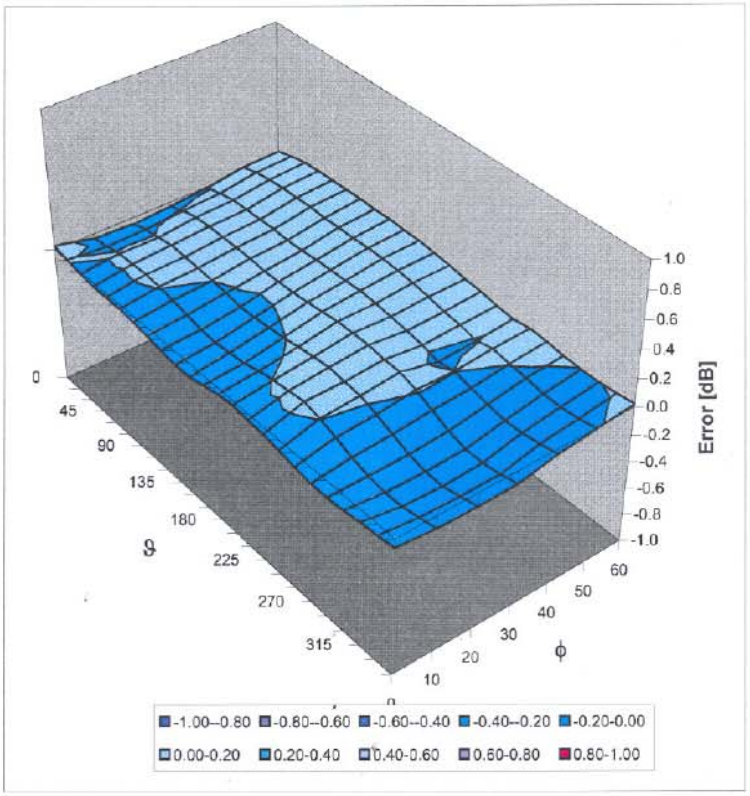
f [MHz]	Validity [MHz][C]	TSL	Permittivity	Conductivity	Alpha	Depth	ConvF Uncertainty
2300	± 50 / ± 100	Head	39.4 ± 5%	1.71 ± 5%	0.76	0.52	7.73 ± 11.8% (k=2)
2600	± 50 / ± 100	Head	39.0 ± 5%	1.96 ± 5%	0.62	0.60	7.31 ± 11.8% (k=2)
3500	± 50 / ± 100	Head	37.9 ± 5%	2.91 ± 5%	0.36	1.03	7.09 ± 13.1% (k=2)
2300	± 50 / ± 100	Body	52.8 ± 5%	1.85 ± 5%	0.63	0.64	7.59 ± 11.8% (k=2)
2600	± 50 / ± 100	Body	52.5 ± 5%	2.16 ± 5%	0.52	0.76	6.91 ± 11.8% (k=2)
3500	± 50 / ± 100	Body	51.3 ± 5%	3.31 ± 5%	0.40	1.33	6.32 ± 13.1% (k=2)
5200	± 50 / ± 100	Body	49.0 ± 5%	5.30 ± 5%	0.35	1.70	4.34 ± 13.1% (k=2)
5300	± 50 / ± 100	Body	48.9 ± 5%	5.42 ± 5%	0.38	1.70	4.06 ± 13.1% (k=2)
5500	± 50 / ± 100	Body	48.6 ± 5%	5.65 ± 5%	0.43	1.70	3.98 ± 13.1% (k=2)
5600	± 50 / ± 100	Body	48.5 ± 5%	5.77 ± 5%	0.35	1.70	4.19 ± 13.1% (k=2)
5800	± 50 / ± 100	Body	48.2 ± 5%	6.00 ± 5%	0.30	1.70	4.20 ± 13.1% (k=2)

[C] The validity of ± 100 MHz only applies for DASY v4.4 and higher (see Page 2). The uncertainty is the RSS of the ConvF uncertainty at calibration frequency and the uncertainty for the indicated frequency band.

EX3DV3 SN:3514 January 31, 2008

Deviation from Isotropy in HSL

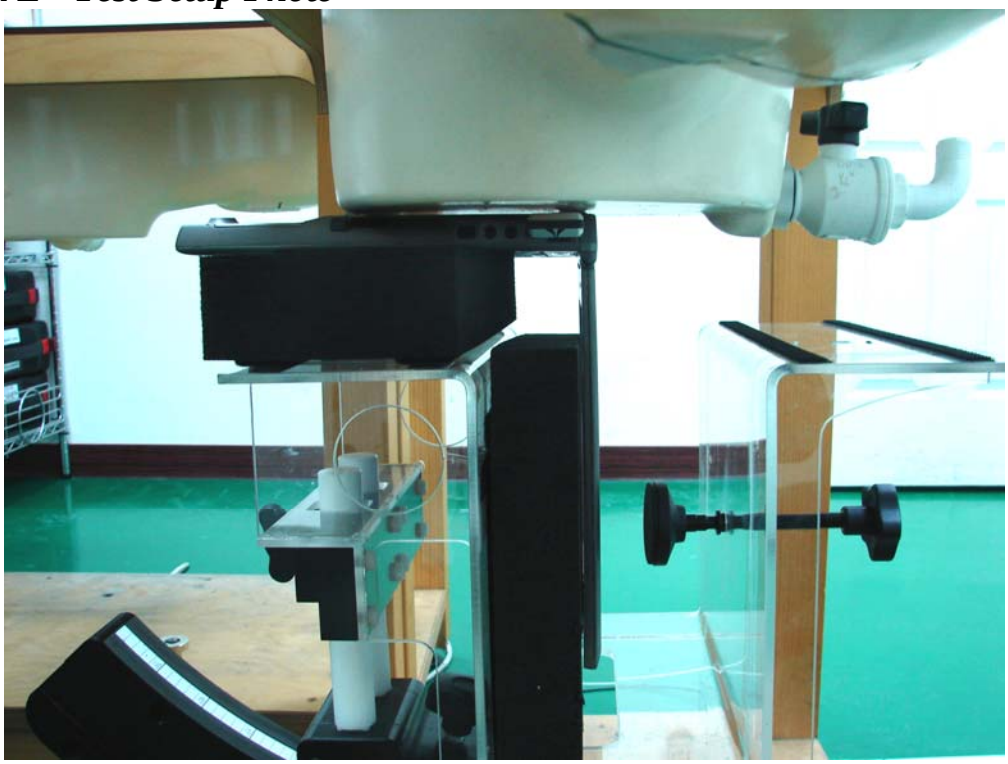
Error (ϕ, ϑ), f = 900 MHz



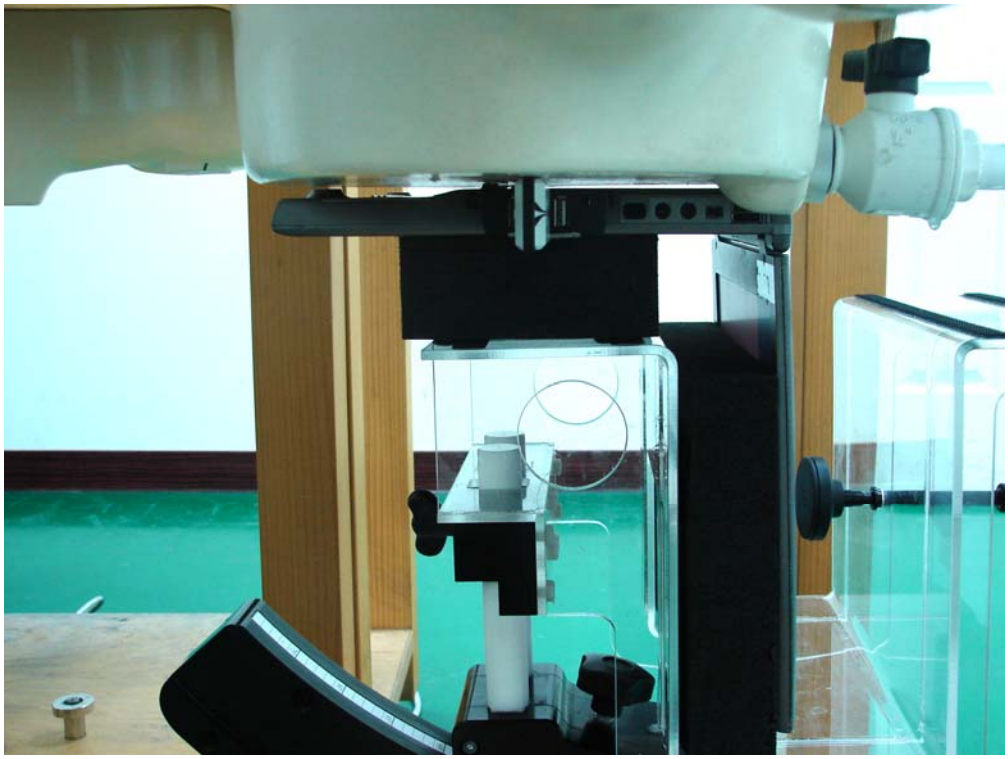
Uncertainty of Spherical Isotropy Assessment: ± 2.6% (k=2)

Appendix D - Product Photo

Appendix E - Test Setup Photo

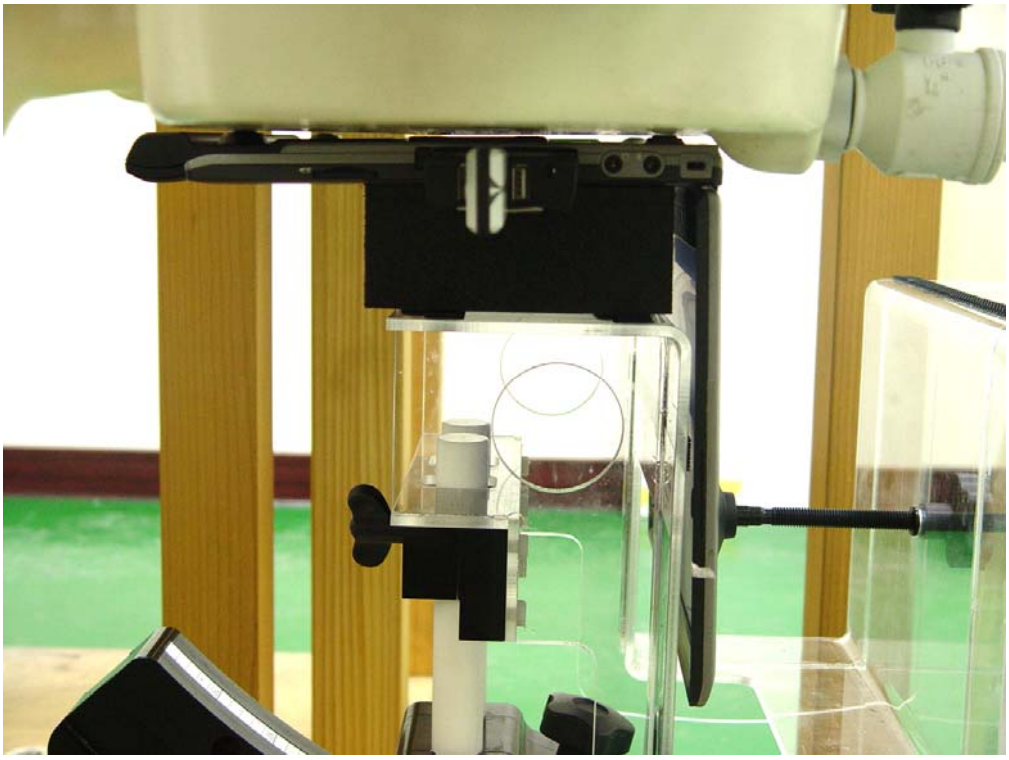


DELL D400 Notebook Bottom with 0cm Gap with Horizontal USB Port



DELL D400 Notebook Bottom with 0cm Gap with Vertical USB Port

DELL D430 Notebook Bottom with 0cm Gap with Horizontal USB Port



DELL D430 Notebook Bottom with 0cm Gap with Vertical USB Port

DELL M2300 Notebook Bottom with 0cm Gap with Horizontal USB Port

DELL M2300 Notebook Bottom with 0cm Gap with Vertical USB Port